

# A compact, low-field, broadband matching section for externallypowered X-band dielectric-loaded accelerating structures

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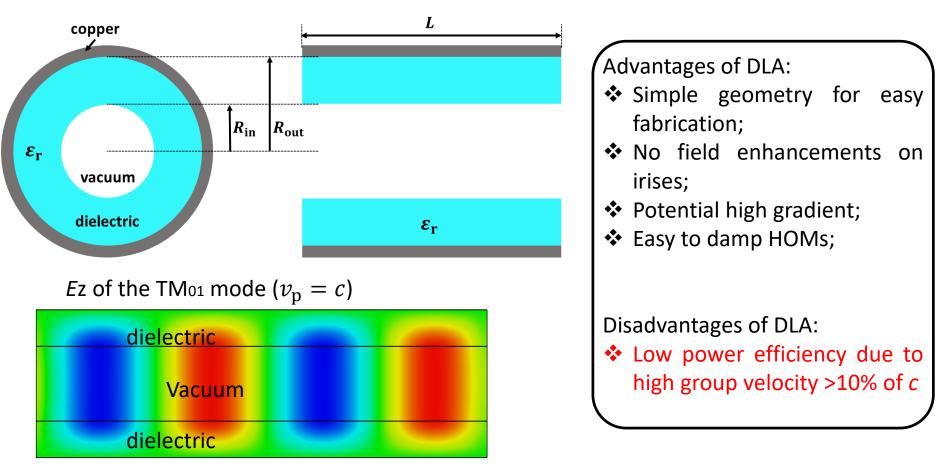
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#### **Presenter: Dr. Yelong Wei**

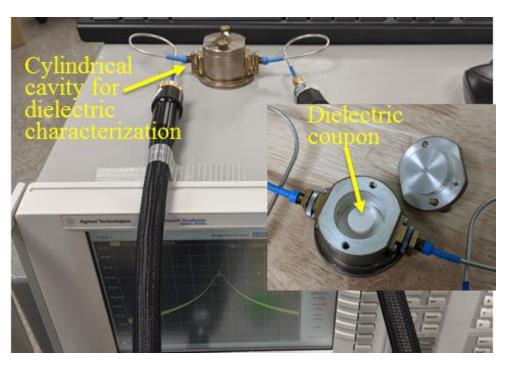
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# Introduction

• Slow wave accelerators: dielectric-loaded accelerating (DLA) structures



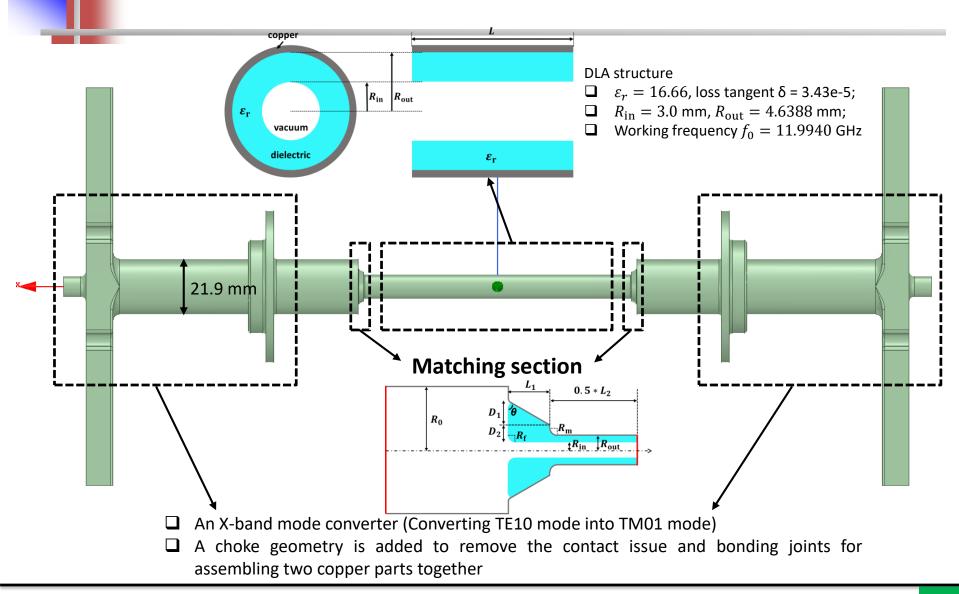
## **Dielectric RF property**



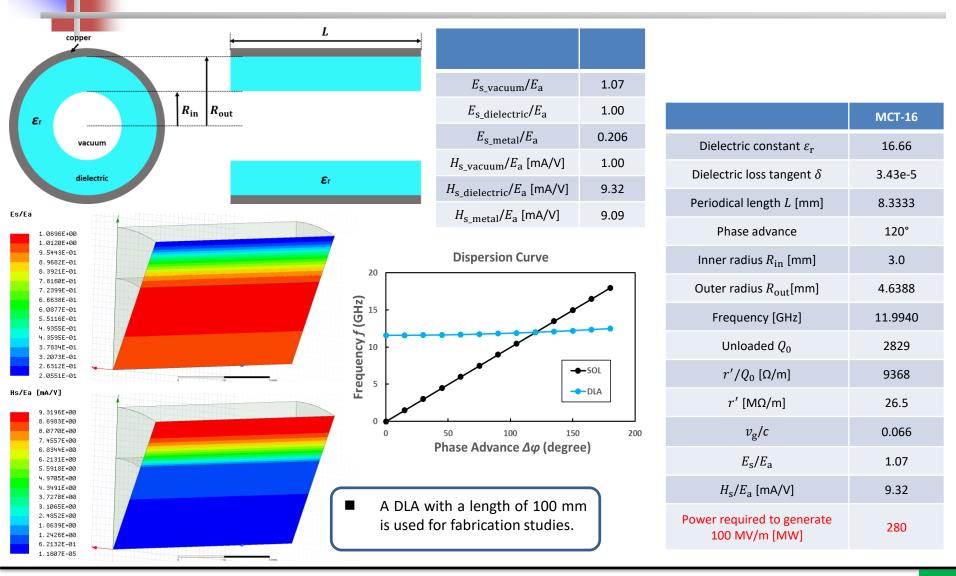
#### Courtesy of photo from Dr. Chunguang Jing, Euclid Techlabs.

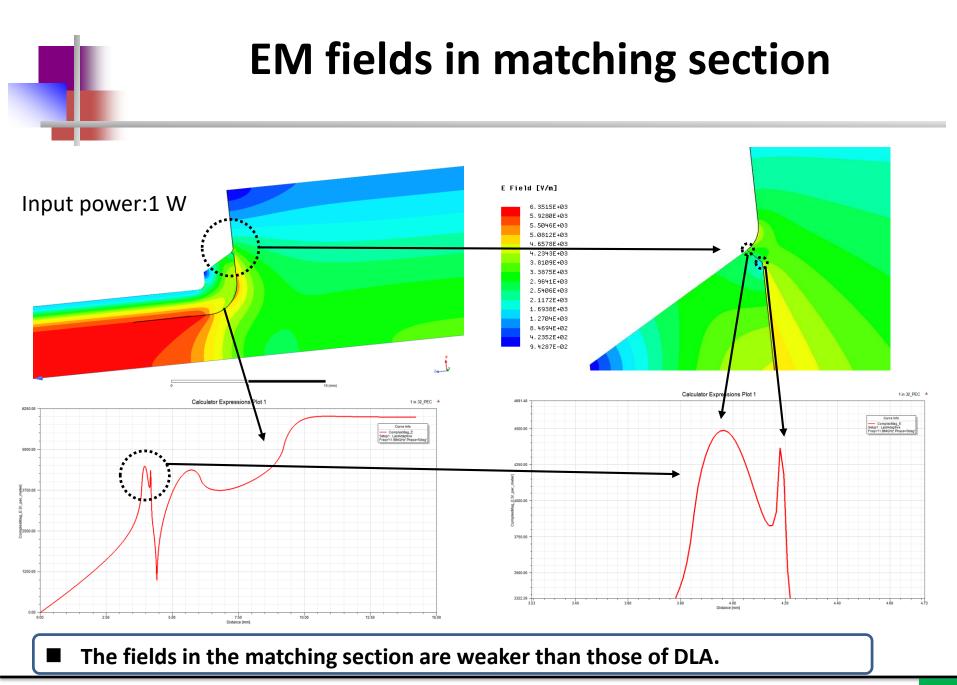
- A  $TE_{01\delta}$  silver-plated resonator with a high quality factor, which is designed for testing ceramics at an X-band frequency, is used to measure the dielectric constant  $\varepsilon_r$  and loss tangent tan $\delta$  of sample coupons.
- Four dielectric coupons made from the same dielectric rods as for the fabrication of the DLA structure are measured.
- A dielectric constant ε<sub>r</sub> = 16.66 and an ultralow loss tangent tanδ = 3.43 × 10<sup>-5</sup> (having error bars 0.6% of the nominal value) are obtained for the RF design of the DLA structure and matching sections which follows.

## **An X-band DLA structure**

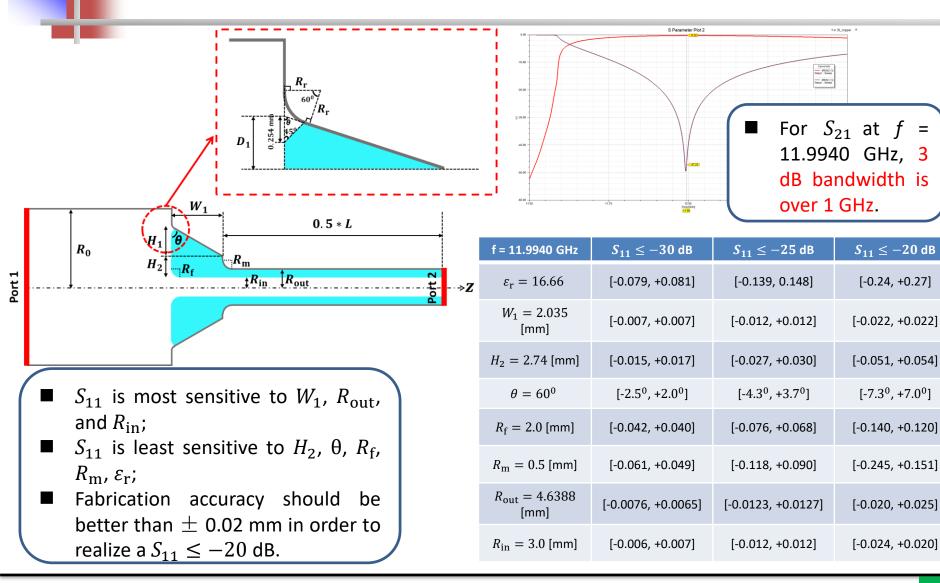


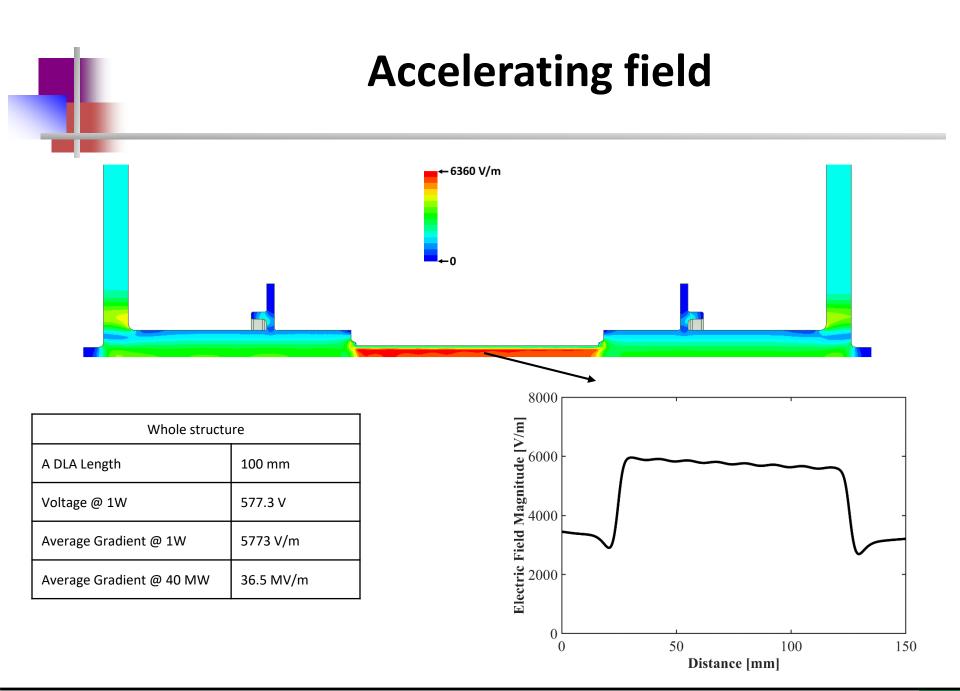
## **RF parameters for a DLA**

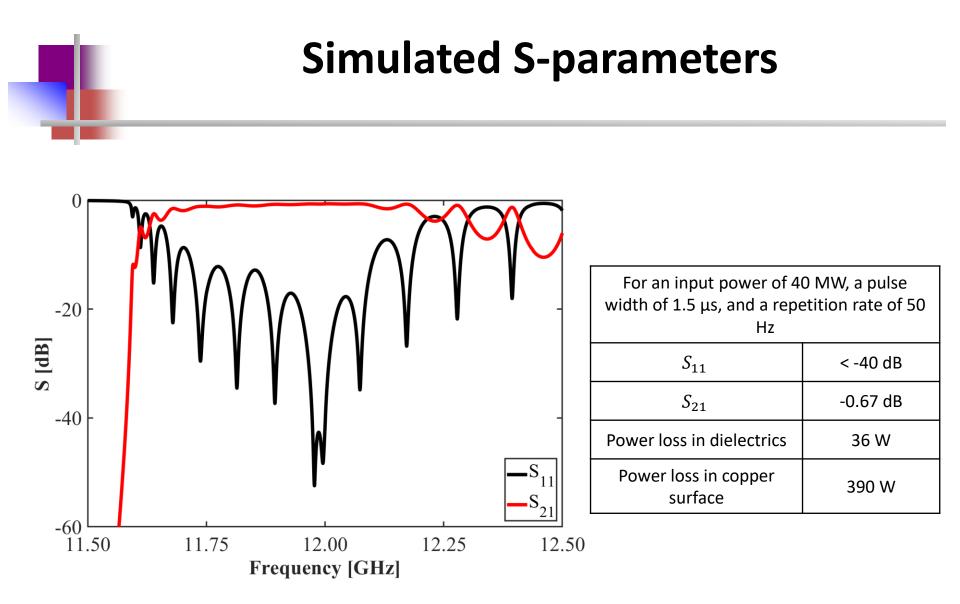




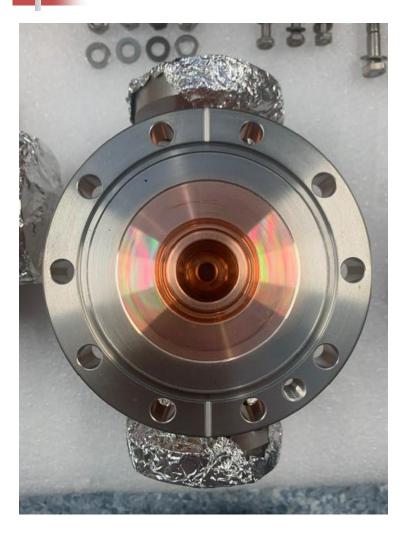
### **Tolerance studies**





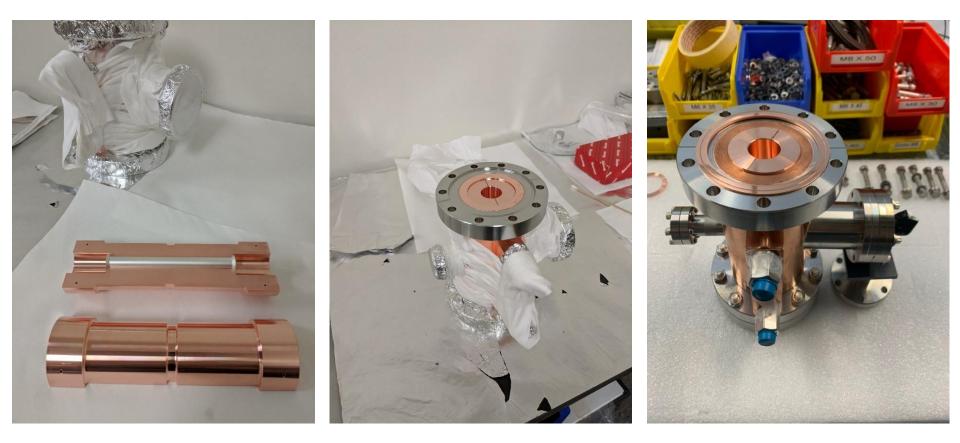


## Mode converters with a choke



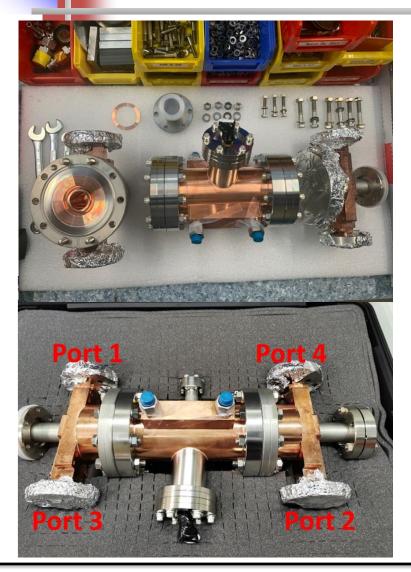


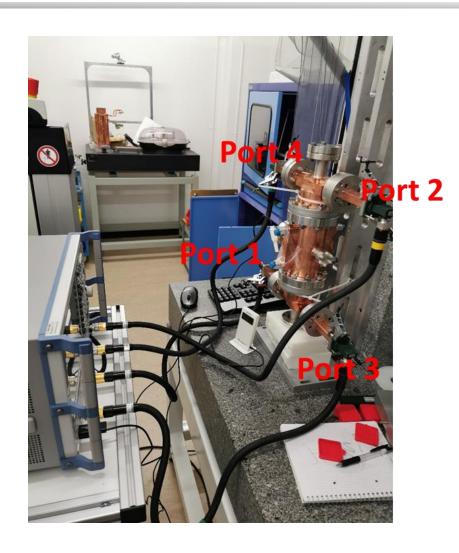
#### **DLA structure**



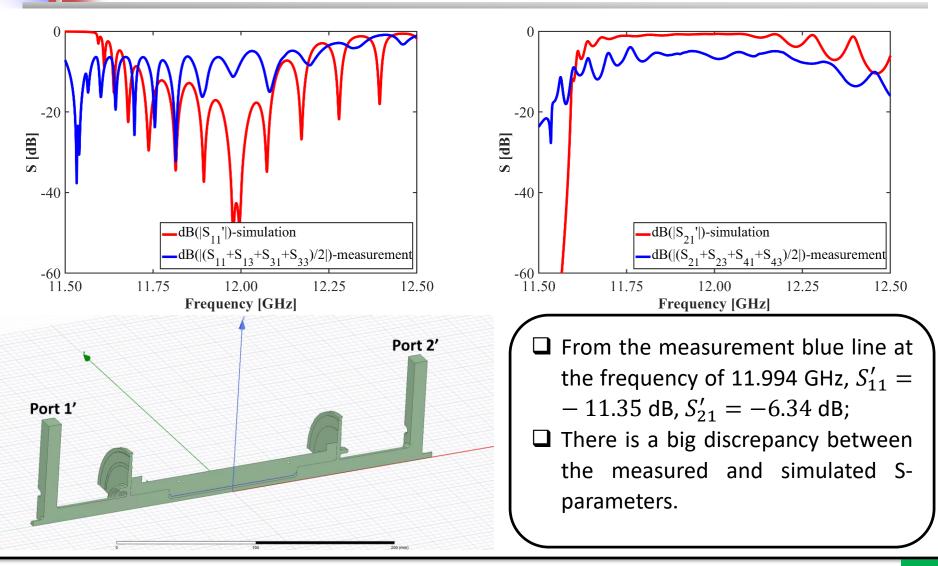
Courtesy of photos from Dr. Chunguang Jing, Euclid Techlabs.

#### **RF Measurement on assembly of two TE10-TM01 mode converters and the DLA structure**





#### **S**-parameters comparison



# Summary & Outlook

- An X-band DLA structure with the TE10-TM01 mode converters and matching sections is designed, fabricated, and low-power measured.
- The fabrication error may cause the big discrepancy between measured and simulated S-parameters.

Using two power splitters for 2-port testing on the DLA structure (Large power loss results from HOMs' propagation due to the asymmetries in the 4-port testing).